

### Description

The SX60N25T uses advanced **Trench** technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as high as 12V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

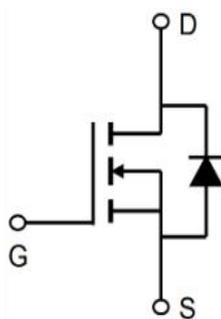
$V_{DS} = 250V$   $I_D = 60A$

$R_{DS(ON)} < 33m\Omega @ V_{GS}=10V$

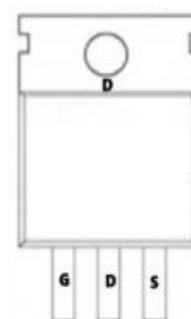
### Application

UPS

BLDC



TO-263-3L



### Absolute Maximum Ratings ( $T_c=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
VDSS	Drain-to-Source Voltage	250	V
ID@TA=25°C	Continuous Drain Current VGS @ 10V	60	A
ID@TA=100°C	Continuous Drain Current VGS @ 10V	40	A
IDM	Pulsed Drain Current (pulse width limited by T <sub>JM</sub> )	230	A
VGS	Gate-to-Source Voltage	±30	V
EAS	Single Pulse Avalanche Energy	300	mJ
EAr1	Avalanche Energy, Repetitive	75	mJ
IAR a1	Avalanche Current	45	A
dv/dt <sup>a2</sup>	Peak Diode Recovery dv/dt	5.0	V/ns
PD	Power Dissipation	360	W
T <sub>J</sub> , T <sub>stg</sub>	Operating Junction and Storage Temperature Range	-55 to 150	°C
TL	Maximum Temperature for Soldering	300	°C
RθJC	Thermal Resistance, Junction-to-Case	0.45	°C/W
RθJA	Thermal Resistance, Junction-to-Ambient	60	°C/W

**Electrical Characteristics@T<sub>j</sub>=25°C(unless otherwise specified)**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
VDSS	Drain to Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	250	--	--	V
IDSS	Drain to Source Leakage Current	V <sub>DS</sub> =250V, V <sub>GS</sub> =0V, T <sub>a</sub> =25°C	--	--	1.0	μA
		V <sub>DS</sub> =250V, V <sub>GS</sub> =0V, T <sub>a</sub> =125°C	--	--	100	
IGSS(F)	Gate to Source Forward Leakage	V <sub>GS</sub> =+20V	--	--	100	nA
IGSS(R)	Gate to Source Reverse Leakage	V <sub>GS</sub> =-20V	--	--	-100	nA
RDS(ON)	Drain-to-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =35A	--	28	33	mΩ
VGS(TH)	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	3.6	--	5.0	V
gfs	Forward Trans conductance	V <sub>DS</sub> =10V, I <sub>D</sub> =35A	100	--	--	S
R <sub>g</sub>	Gate Resistance	V <sub>GS</sub> =0V V <sub>DS</sub> open f=1.0MHz		1.5		Ω
Ciss	Input Capacitance	V <sub>GS</sub> =0V V <sub>DS</sub> =25V f=1.0MHz	--	7000		pF
Coss	Output Capacitance		--	480		pF
Crss	Reverse Transfer Capacitance		--	210		pF
td(ON)	Turn-on Delay Time		--	45	--	ns
t <sub>r</sub>	Rise Time	I <sub>D</sub> =35A, V <sub>DS</sub> =50V V <sub>GS</sub> =10V, R <sub>g</sub> =2.5Ω	--	70	--	ns
td(OFF)	Turn-Off Delay Time		--	110	--	ns
t <sub>f</sub>	Fall Time		--	90	--	ns
Q <sub>g</sub>	Total Gate Charge	I <sub>D</sub> =35A, V <sub>DD</sub> =100V V <sub>GS</sub> =10V	--	200	--	nC
Q <sub>gs</sub>	Gate to Source Charge		--	28	--	nC
Q <sub>gd</sub>	Gate to Drain ("Miller") Charge		--	60	--	nC
ISD	Continuous Source Current (Body Diode)		--	--	58	A
ISM	Maximum Pulsed Current (Body Diode)		--	--	230	A
VSD	Diode Forward Voltage	I <sub>S</sub> =35A, V <sub>GS</sub> =0V	--	--	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>S</sub> =30A, T <sub>j</sub> =25°C, V <sub>DD</sub> =50V dI <sub>F</sub> /dt=100A/μs, V <sub>GS</sub> =0V	--	120	--	ns
Q <sub>rr</sub>	Reverse Recovery Charge		--	0.55	--	uC

**Note :**

- 1、 The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- 2、 The EAS data shows Max. rating . I<sub>AS</sub> = 35A, R<sub>G</sub> = 25Ω, V<sub>DD</sub>=50V , V<sub>GS</sub>=10V, Starting T<sub>J</sub> = 25 °C
- 3、 The test condition is Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 1%
- 4、 The power dissipation is limited by 150°C junction temperature
- 5、 The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

Typical Characteristics

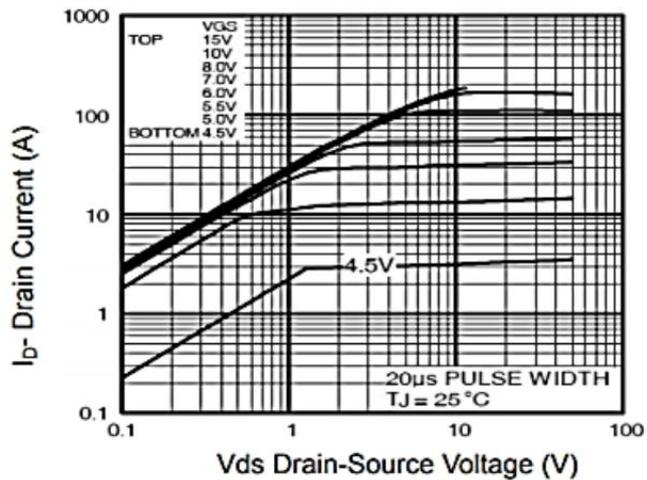


Figure 1 Output Characteristics

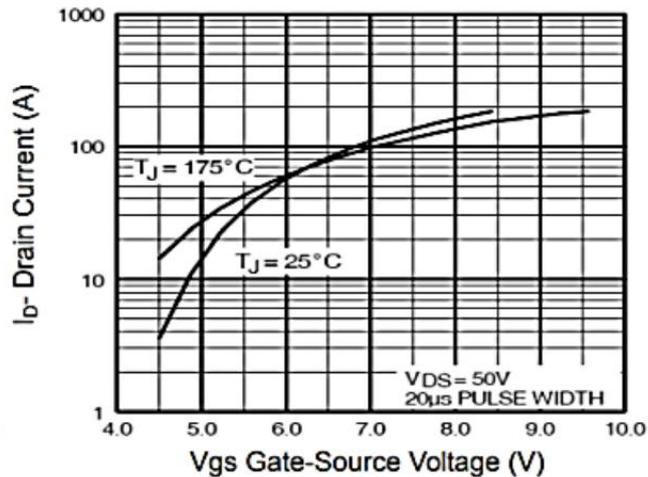


Figure 2 Transfer Characteristics

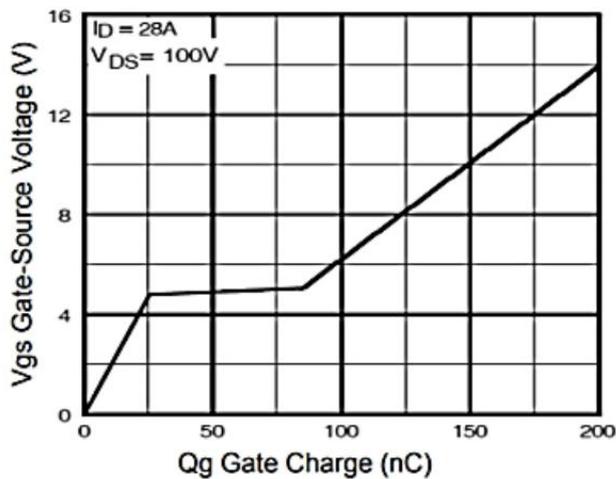


Figure 5 Gate Charge

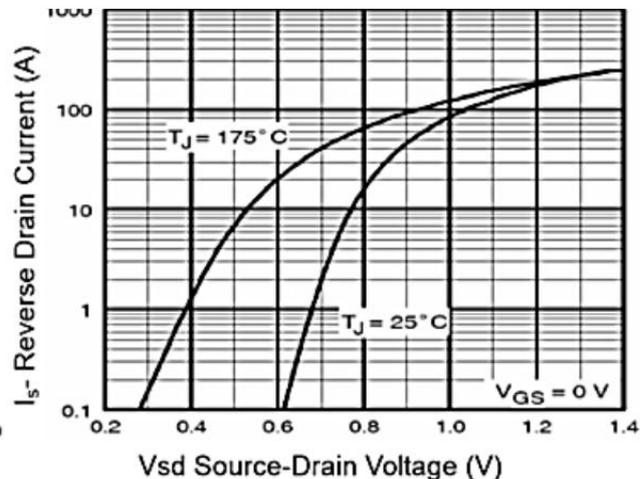


Figure 6 Source-Drain Diode Forward

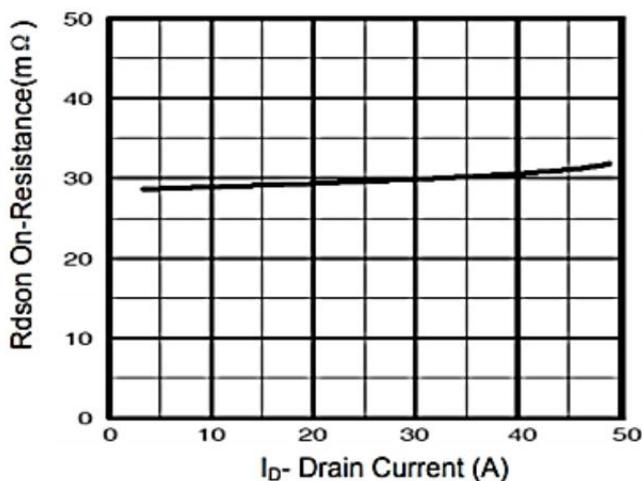


Figure 3 Rdson-Drain Current

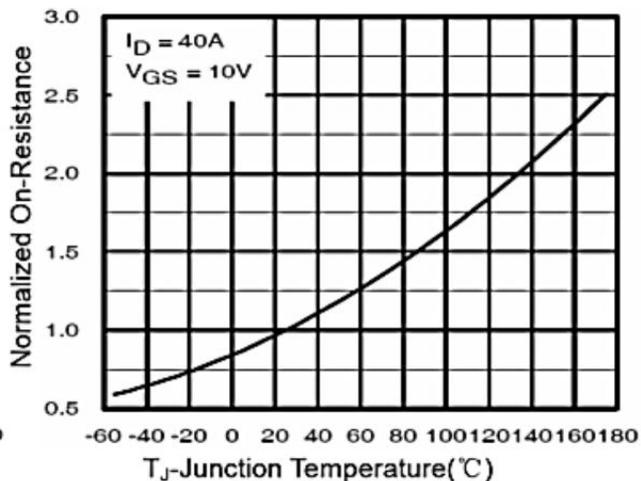


Figure 4 Rdson-Junction Temperature

Typical Characteristics

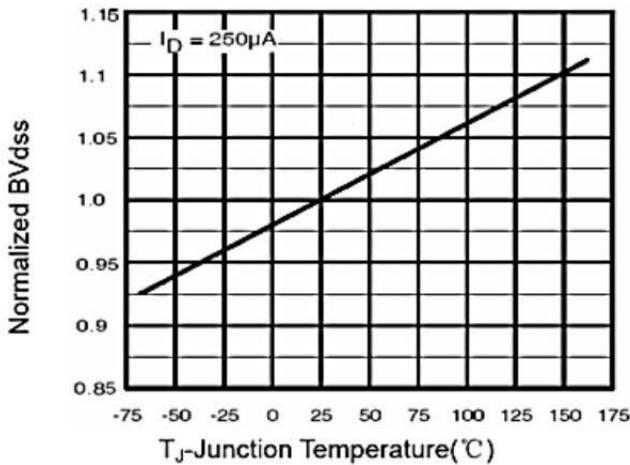


Figure 9  $BV_{DSS}$  vs Junction Temperature

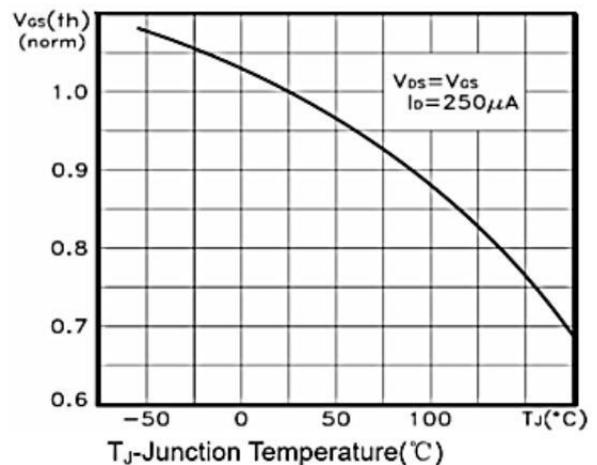


Figure 10  $V_{GS(th)}$  vs Junction Temperature

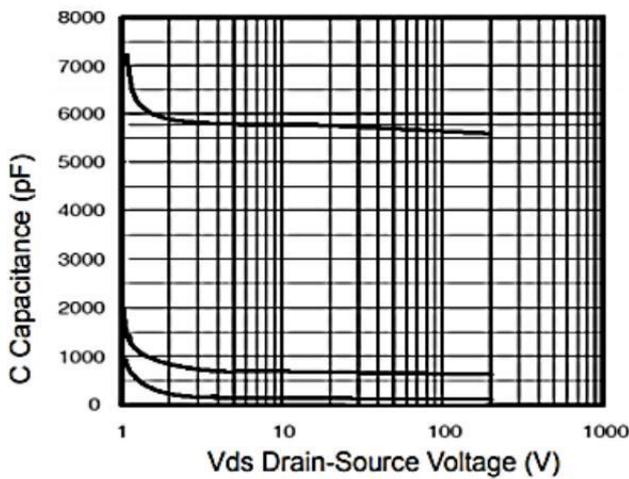


Figure 7 Capacitance vs  $V_{ds}$

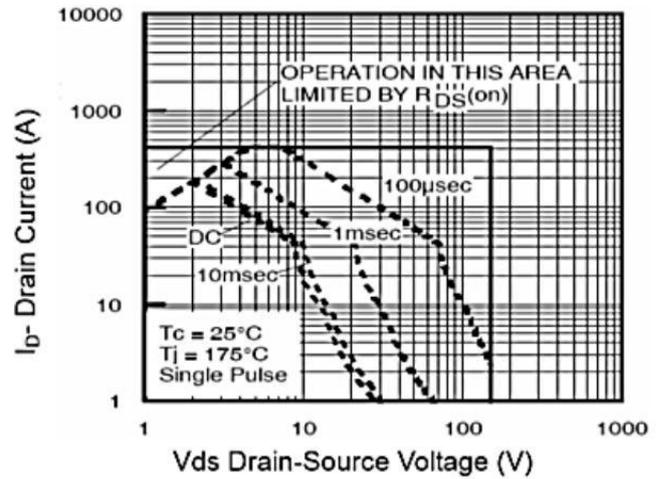


Figure 8 Safe Operation Area

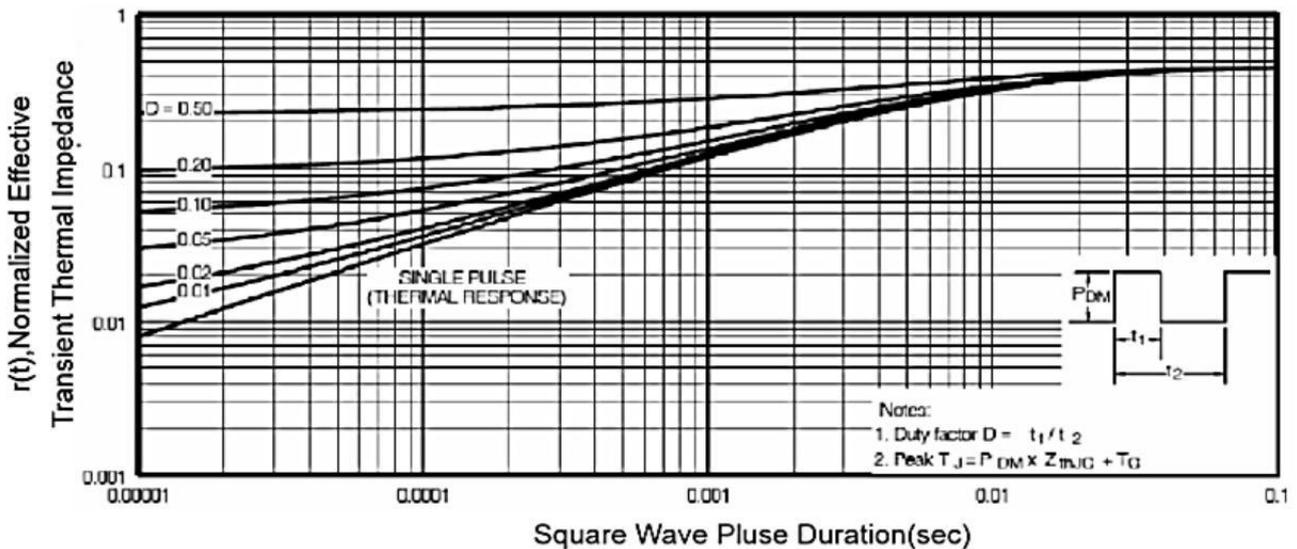
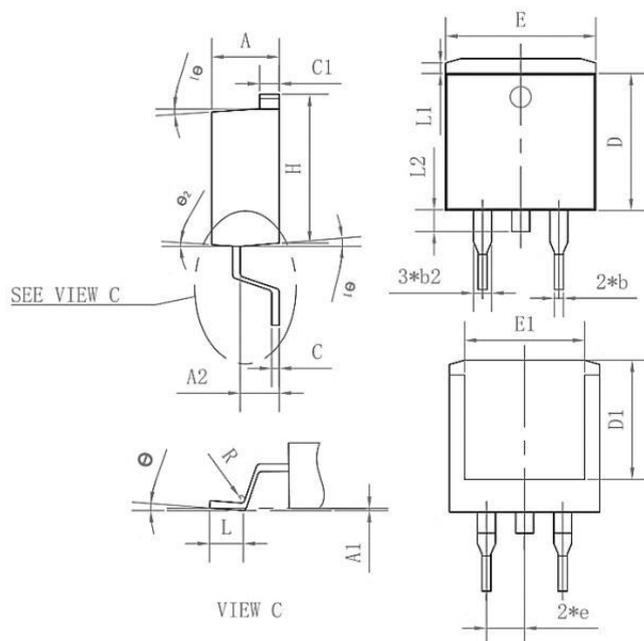


Figure 11 Normalized Maximum Transient Thermal Impedance

**Package Mechanical Data-TO-263-3L-SLK**



Symbol	Common		
	Mim	Nom	Max
A	4.35	4.47	4.60
A1	0.09	0.10	0.11
A2	2.30	2.40	2.70
b	0.70	0.80	1.00
b2	1.25	1.36	1.50
C	0.45	0.50	0.65
C1	1.29	1.30	9.40
D	9.10	9.20	9.30
D1	7.90	8.00	8.10
E	9.85	10.00	10.20
E1	7.90	8.00	8.10
H	15.30	15.50	15.70
e	-	2.54	-
L	2.34	2.54	2.74
L1	1.00	1.10	1.20
L2	1.30	1.40	1.50
R	0.24	0.25	0.26
θ	0°	4°	8°
θ1	4°	7°	10°
θ2	0°	3°	6°

**Package Marking and Ordering Information**

Product ID	Pack	Marking	Qty(PCS)
TAPING	TO-263-3L		800